

Search Notes

Application/Control No.

10/766,710

Examiner

Kin-Chan Chen

Applicant(s)/Patent under
Reexamination

LEE, HEON

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	700	3/14/2006	KCC
	702		
	703		
	706		
438	714		
216	8		
216	72		
430	320		
430	323	3/14/06	KCC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Exact key words search USPTO, USPG-Pub., EP, JPO, Derwent, IBM-TDB. inventor search	3/14/2006	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438	700	3/16/06	KCC
	702		
	703		
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